


<b>Search Notes</b>  	<b>Application/Control No.</b>  10802762	<b>Applicant(s)/Patent Under Reexamination</b>  LEE ET AL.
	<b>Examiner</b>  PHYOWAI LIN	<b>Art Unit</b>  2613

### SEARCHED

Class	Subclass	Date	Examiner
398	182-201	03/31/08	PWL
359	237-238, 276-279	03/31/08	PWL

### SEARCH NOTES

Search Notes	Date	Examiner
USPA, US-PUG, EPO, JPO	03/31/08	PWL
IEEE	04/02/08	PWL
SPICE	04/02/08	PWL
GOOGLE	04/02/08	PWL

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
398	all	04/03/08	PWL
	text search	04/03/08	PWL